

Notice of References Cited	Application/Control No. 10/687,930		Applicant(s)/Patent Under Reexamination YOSHIOKA ET AL.	
	Examiner Sophia S. Chen		Art Unit 2852	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,311,756	01-1982	Brooksbank, Wallace R.	428/57(X)
*	B	US-5,321,480	06-1994	Merle et al.	399/329
*	C	US-5,489,972	02-1996	Shuster et al.	399/313
*	D	US-5,697,030	12-1997	Hayashi et al.	399/312(X)
*	E	US-5,951,441	09-1999	Dalebout et al.	474/253(X)
*	F	US-6,009,290	12-1999	Mochida, Yoshinori	399/162
*	G	US-6,181,889 B1	01-2001	Hayano et al.	399/162(X)
*	H	US-6,312,778 B1	11-2001	Sandell, Karl-H.ang.kan	428/57
*	I	US-2002/0170806 A1	11-2002	Engle et al.	198/844.2
*	J	US-6,618,570 B2	09-2003	Yuan et al.	399/303
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	06-043768 A	02-1994	Japan	Honobe	-----/-----
	O	11-212422 A	08-1999	Japan	Uda et al.	-----/-----
	P	2000-330422 A	11-2000	Japan	Torio	-----/-----
	Q	2001-066907 A	03-2001	Japan	Kato et al.	-----/-----
	R	2001-215845 A	08-2001	Japan	Hayashi	-----/-----
	S	2002-082540 A	03-2002	Japan	Fujita	-----/-----
	T	2002-091194 A	03-2002	Japan	Fujita	-----/-----

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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